ENGINEERING TEST REPORT

APR. 23, 2004

Report No. CALR-FCC-254

This is to certify that the MICROWAVE OVEN from which the following data has been derived properly complies with the requirements of " FCC Rules and Regulations Part 18 Subpart C " as of the date the measurements were made.

1. Manufacturer of Device:

Shanghai Matsushita Microwave Oven Company Ltd.

898 Long Dong Road, Shanghai Shanghai 201203, China

2. Description of Device

a. FCC ID.b. Model No.

c. Serial No.
d. Operating Frequency
e. Output RF Power

f. Power Consumption
g. Magnetron Type

i. Employed Modeii. Door Seal Type

: ACLAP6S21

NN-S335WF PP0001

2450 MHz 800 W (BY IEC 705)

120 V. 60 Hz Matsushita 2M211

: Turn table : Choke

3. Measurement Procedure Used : FCC/OST MP-5

4. Measurement Site

Name

Panasonic Magnetron Lab. Panasonic Industrial Company

Address

1707 N. Randall Road

Elgin, Illinois 60123-7847

Description of this test facility has been filed with the FCC. (Feb. 26, 1987, File # 31010/EQU 4-3-0A)

5. Date of Measurement : APR. 23, 2004

6. Measurement Data : See Attached "Data Summary"

Tested By

Mitsuhiro Okamoto

Applications Manager of Magnetron Panasonic Industrial Company

ENGINEERING TEST REPORT

APR. 23, 2004

Report No. CALR-FCC-255

This is to certify that the MICROWAVE OVEN from which the following data has been derived properly complies with the requirements of " FCC Rules and Regulations Part 18 Subpart C " as of the date the measurements were made.

1. Manufacturer of Device : Shanghai Matsushita Microwave Oven Company Ltd.

898 Long Dong Road, Shanghai Shanghai 201203, China

2. Description of Device

a. FCC ID. : ACLAP6S21
b. Model No. : NN-S335WF
c. Serial No. : PP0002
d. Operating Frequency : 2450 MHz

e. Output RF Power : 800 W (BY IEC 705) f. Power Consumption : 120 V. 60 Hz

g. Magnetron Type : Samsung OM52S
h. Employed Mode : Turn table
i. Door Seal Type : Choke

3. Measurement Procedure Used : FCC/OST MP-5

4. Measurement Site

Name : Panasonic Magnetron Lab.

Panasonic Industrial Company

Address : 1707 N. Randall Road

Elgin, Illinois 60123-7847

Description of this test facility has been filed with the FCC. (Feb. 26, 1987, File # 31010/EQU 4-3-0A)

5. Date of Measurement : APR. 23, 2004

6. Measurement Data

: See Attached "Data Summary"

Tested By

Mitsuhiro Okamoto

Applications Manager of Magnetron Panasonic Industrial Company